

**Search Notes**

Application/Control No.

10/521,683

Examiner

Hai H. Huynh

Applicant(s)/Patent under  
Re examination

SCHMIDT ET AL.

Art Unit

3747

**SEARCHED**

Class	Subclass	Date	Examiner
123	598	5/23/2006	HHH
123	599	5/23/2006	HHH
123	601	5/23/2006	HHH
123	605-606	5/23/2006	HHH
123	608	5/23/2006	HHH
123	143B	5/23/2006	HHH
123	634	5/23/2006	HHH
333	246-248	5/23/2006	HHH
333	99PL	5/23/2006	HHH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	5/23/2006	HHH